# MSKSEMI















**ESD** 

TVS

TSS

MOV

**GDT** 

**PLED** 

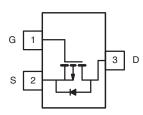
# Brodnet data speet

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SOT-23



#### **Features**

- $-30V, -4.0A, RDS(ON) = 45m\Omega@VGS = -10V$
- Fast switching
- Green Device Available
- Suit for -4.5V Gate Drive Applications

#### **Applications**

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-30V	45mΩ	-4.0A

#### Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-30	V
V <sub>G</sub> s	Gate-Source Voltage	±20	V
•	Drain Current – Continuous (T <sub>A</sub> =25°C)	-4.0	А
D	Drain Current – Continuous (T <sub>A</sub> =70°C)	-3.0	А
Ірм	Drain Current – Pulsed¹	-16	А
D.	Power Dissipation (T <sub>A</sub> =25°C)	1.56	W
$P_{D}$	Power Dissipation – Derate above 25°C	0.012	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient		80	°C/W



#### Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA		-30			٧
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.03		V/°C
1	Drain Source Lookage Current	$V_{DS}$ =-30V , $V_{GS}$ =0V , $T_J$ =25°C			-1	uA
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			<b>-</b> 10	uA
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA

#### **On Characteristics**

D	Static Drain-Source On-Resistance	$V_{GS}$ =-10V , $I_D$ =-3A		45	60	mΩ
R <sub>DS(ON)</sub> Static Drain-Source On-Resistance		$V_{GS}$ =-4.5 $V$ , $I_D$ =-2 $A$		60	85	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA		<b>-</b> 1.6	<b>-</b> 2.2	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient			4		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-3A		3.5		S

#### **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>2, 3</sup>			5.1	
$Q_{gs}$	Gate-Source Charge <sup>2, 3</sup>	V <sub>DS</sub> =-15V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		2	 nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>			2.2	
$T_{d(on)}$	Turn-On Delay Time <sup>2, 3</sup>			3.4	
Tr	Rise Time <sup>2, 3</sup>	$V_{DD}$ =-15V , $V_{GS}$ =-10V , $R_G$ =6 $\Omega$		10.8	 
$T_{d(off)}$	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =-1A		26.9	 ns
$T_f$	Fall Time <sup>2, 3</sup>			6.9	
Ciss	Input Capacitance			560	
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , F=1MHz		55	 pF
Crss	Reverse Transfer Capacitance	1		40	

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions		Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V . Force Current			<b>-</b> 4.0	Α
I <sub>SM</sub>	Pulsed Source Current	VG-VD-UV, FOICE Cullent			<b>-</b> 8.0	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			<b>-</b> 1.2	V

#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%. Essentially independent of operating temperature.

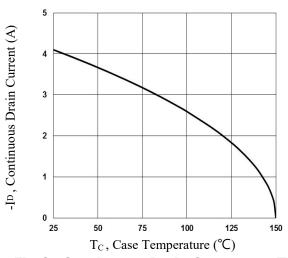


Fig.1 Continuous Drain Current vs. Tc

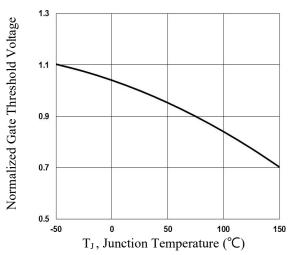


Fig.3 Normalized  $V_{th}$  vs.  $T_J$ 

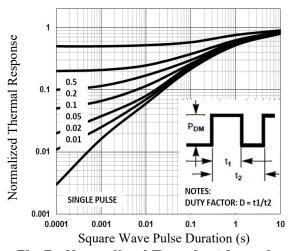


Fig.5 Normalized Transient Impedance

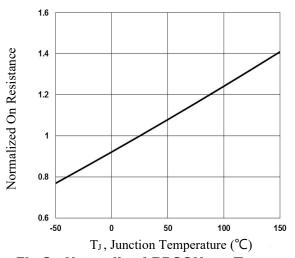


Fig.2 Normalized RDSON vs. T<sub>J</sub>

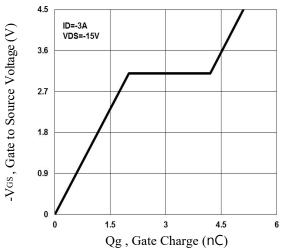


Fig.4 Gate Charge Waveform

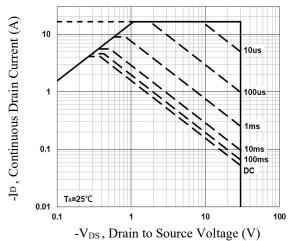
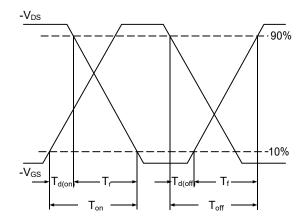


Fig.6 Maximum Safe Operation Area







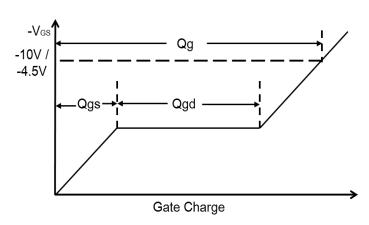
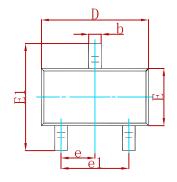


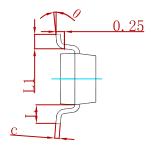
Fig.8 Gate Charge Waveform

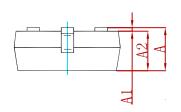


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#### PACKAGE MECHANICAL DATA

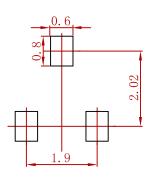






Symbol	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
Е	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF 0.022 REI		REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

## **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

### **REEL SPECIFICATION**

P/N	PKG	QTY
SI2343DS-T1-E3-MS	SOT-23	3000



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